

ANY-RATE PRECISION CLOCK MULTIPLIER/JITTER ATTENUATOR

Description

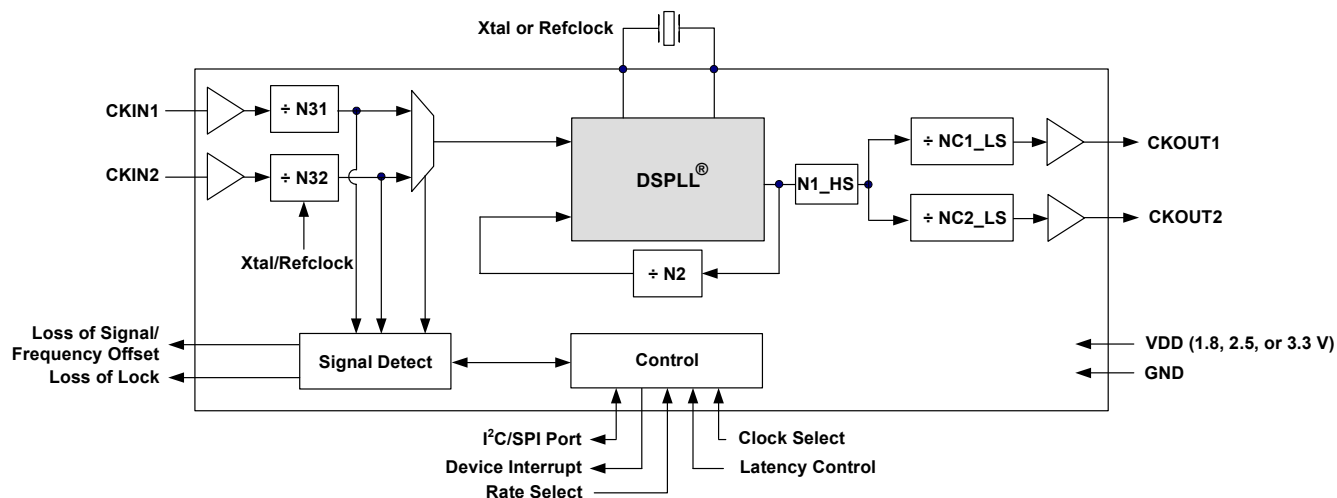
The Si5326 is a jitter-attenuating precision clock multiplier for applications requiring sub 1 ps jitter performance. The Si5326 accepts two input clocks ranging from 2 kHz to 710 MHz and generates two output clocks ranging from 2 kHz to 945 MHz and select frequencies to 1.4 GHz. The two outputs are divided down separately from a common source. The Si5326 can also use its crystal oscillator as a clock source for frequency synthesis. The device provides virtually any frequency translation combination across this operating range. The Si5326 input clock frequency and clock multiplication ratio are programmable through an I²C or SPI interface. The Si5326 is based on Silicon Laboratories' 3rd-generation DSPLL[®] technology, which provides any-rate frequency synthesis and jitter attenuation in a highly integrated PLL solution that eliminates the need for external VCXO and loop filter components. The DSPLL loop bandwidth is digitally programmable, providing jitter performance optimization at the application level. Operating from a single 1.8, 2.5, or 3.3 V supply, the Si5326 is ideal for providing clock multiplication and jitter attenuation in high performance timing applications.

Applications

- SONET/SDH OC-48/OC-192/STM-16/STM-64 line cards
- GbE/10GbE, 1/2/4/8/10GFC line cards
- ITU G.709 and custom FEC line cards
- Optical modules
- Wireless basestations
- Data converter clocking
- xDSL
- SONET/SDH + PDH clock synthesis
- Test and measurement
- Synchronous Ethernet
- Broadcast video

Features

- Generates any frequency from 2 kHz to 945 MHz and select frequencies to 1.4 GHz from an input frequency of 2 kHz to 710 MHz
- Ultra-low jitter clock outputs with jitter generation as low as 0.3 ps rms (50 kHz–80 MHz)
- Integrated loop filter with selectable loop bandwidth (60 Hz to 8.4 kHz)
- Meets OC-192 GR-253-CORE jitter specifications
- Dual clock inputs w/manual or automatically controlled hitless switching
- Dual clock outputs with selectable signal format (LVPECL, LVDS, CML, CMOS)
- Support for ITU G.709 and custom FEC ratios (255/238, 255/237, 255/236)
- LOL, LOS, FOS alarm outputs
- Digitally-controlled output phase adjustment
- I²C or SPI programmable
- On-chip voltage regulator for 1.8 ±5%, 2.5 ±10%, or 3.3 V ±10% operation
- Small size: 6 x 6 mm 36-lead QFN
- Pb-free, ROHS compliant



Si5326

Table 1. Performance Specifications

($V_{DD} = 1.8 \pm 5\%$, $2.5 \pm 10\%$, or $3.3 \pm 10\%$, $T_A = -40$ to 85 °C)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Temperature Range	T_A		-40	25	85	°C
Supply Voltage	V_{DD}		2.97	3.3	3.63	V
			2.25	2.5	2.75	V
			1.71	1.8	1.89	V
Supply Current	I_{DD}	$f_{OUT} = 622.08$ MHz Both CKOUTs enabled LVPECL format output	—	251	279	mA
		CKOUT2 disabled	—	217	243	mA
		$f_{OUT} = 19.44$ MHz Both CKOUTs enabled CMOS format output	—	204	234	mA
		CKOUT2 disabled	—	194	220	mA
		Disable Mode	—	165	—	mA
Input Clock Frequency (CKIN1, CKIN2)	CK_F	Input frequency and clock multiplication ratio determined by programming device PLL dividers. Consult Silicon Laboratories configuration software	0.002	—	710	MHz
Output Clock Frequency (CKOUT1, CKOUT2)	CK_{OF}	DSPLLsim to determine PLL divider settings for a given input frequency/clock multiplication ratio combination.	0.002	—	945	MHz
			970	—	1134	
			1213	—	1400	
3-Level Input Pins						
Input Mid Current	I_{IMM}	See Note 2.	-2	—	2	µA
Input Clocks (CKIN1, CKIN2)						
Differential Voltage Swing	CKN_{DPP}		0.25	—	1.9	V _{PP}
Common Mode Voltage	CKN_{VCM}	1.8 V ±5%	0.9	—	1.4	V
		2.5 V ±10%	1.0	—	1.7	V
		3.3 V ±10%	1.1	—	1.95	V
Rise/Fall Time	CKN_{TRF}	20–80%	—	—	11	ns
Duty Cycle (Minimum Pulse Width)	CKN_{DC}	Whichever is smaller	40	—	60	%
			2	—	—	ns
Output Clocks (CKOUT1, CKOUT2)						
Common Mode	V_{OCM}	LVPECL	$V_{DD} - 1.42$	—	$V_{DD} - 1.25$	V
Differential Output Swing	V_{OD}	100 Ω load	1.1	—	1.9	
Single Ended Output Swing	V_{SE}	line-to-line $f_{OUT} < 700$ MHz	0.5	—	0.93	V
Rise/Fall Time	CKO_{TRF}	20–80%, $f_{OUT} = 622.08$ MHz	—	350	450	ps
Differential Duty Cycle Uncertainty	CKO_{DC}	LVPECL 100 Ω load line-to-line Measured at 50% point	—	—	±40	ps
Notes:						
1. For a more comprehensive listing of device specifications, please consult the Silicon Laboratories Any-Rate Precision Clock Family Reference Manual. This document can be downloaded from www.silabs.com/timing .						
2. This is the amount of leakage that the 3-level input can tolerate from an external driver. See the Family Reference Manual. In most designs an external resistor voltage divider is recommended.						

Table 1. Performance Specifications (Continued) $(V_{DD} = 1.8 \pm 5\%, 2.5 \pm 10\%, \text{ or } 3.3 \text{ V} \pm 10\%, T_A = -40 \text{ to } 85 \text{ }^\circ\text{C})$

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
PLL Performance						
Jitter Generation $f_{IN} = f_{OUT} = 622.08 \text{ MHz}$ LVPECL output format BWSEL_REG[3:0]=0xA	J_{GEN}	50 kHz–80 MHz	—	0.32	0.42	ps rms
		12 kHz–20 MHz	—	0.31	0.41	ps rms
		800 Hz–80 MHz	—	0.4	0.45	ps rms
Jitter Transfer	J_{PK}		—	0.05	0.1	dB
External Reference Jitter Transfer	J_{PKEXTN}		—	30	—	kHz
Phase Noise	CKO_{PN}	$f_{OUT} = 622.08 \text{ MHz}$ 100 Hz offset	—	–65	–50	dBc/Hz
		1 kHz offset	—	–95	–87	dBc/Hz
		10 kHz offset	—	–110	–100	dBc/Hz
		100 kHz offset	—	–117	–110	dBc/Hz
		1 MHz offset	—	–130	–125	dBc/Hz
Subharmonic Noise	SP_{SUBH}	Phase Noise @ 100 kHz Offset	—	–90	–85	dBc
Spurious Noise	SP_{SPUR}	Max spur @ $n \times F_3$ ($n \geq 1, n \times F_3 < 100 \text{ MHz}$)	—	–98	–75	dBc
Package						
Thermal Resistance Junction to Ambient	Theta JA	Still Air	—	38	—	$^\circ\text{C/W}$
Notes:						
1. For a more comprehensive listing of device specifications, please consult the Silicon Laboratories Any-Rate Precision Clock Family Reference Manual. This document can be downloaded from www.silabs.com/timing .						
2. This is the amount of leakage that the 3-level input can tolerate from an external driver. See the Family Reference Manual. In most designs an external resistor voltage divider is recommended.						

Table 2. Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
DC Supply Voltage	V_{DD}	–0.5 to 3.6	V
LVC MOS Input Voltage	V_{DIG}	–0.3 to ($V_{DD} + 0.3$)	V
Operating Junction Temperature	T_{JCT}	–55 to 150	$^\circ\text{C}$
Storage Temperature Range	T_{STG}	–55 to 150	$^\circ\text{C}$
ESD HBM Tolerance (100 pF, 1.5 k Ω); All pins except CKIN+/CKIN–		2	kV
ESD MM Tolerance; All pins except CKIN+/CKIN–		200	V
ESD HBM Tolerance (100 pF, 1.5 k Ω); CKIN+/CKIN–		700	V
ESD MM Tolerance; CKIN+/CKIN–		150	V
Latch-Up Tolerance		JESD78 Compliant	
Note: Permanent device damage may occur if the Absolute Maximum Ratings are exceeded. Functional operation should be restricted to the conditions as specified in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods of time may affect device reliability.			

155.52 MHz in, 622.08 MHz out

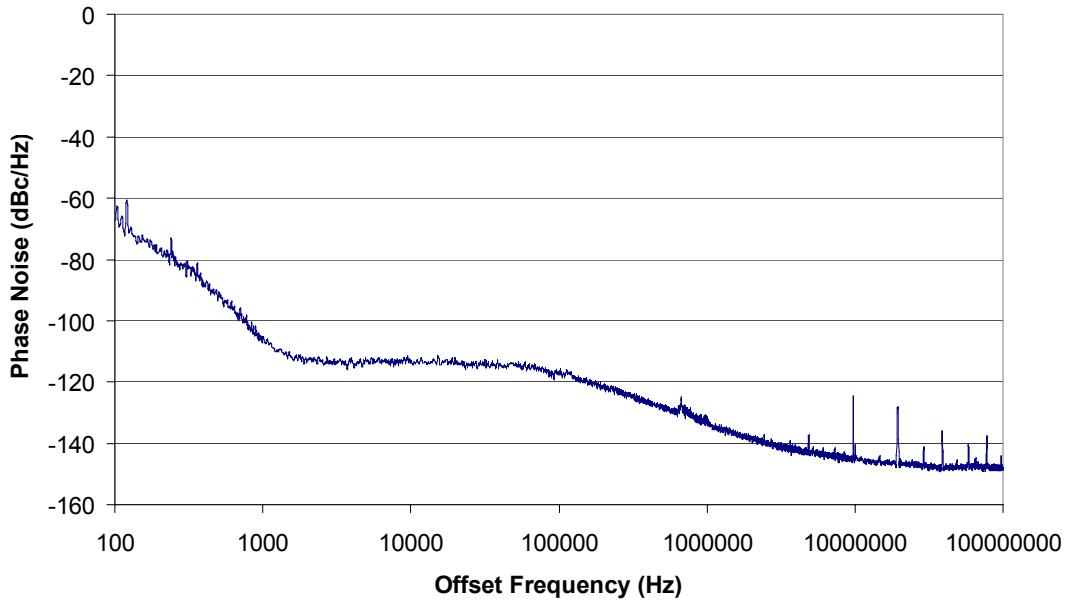


Figure 1. Typical Phase Noise Plot

Jitter Band	Jitter, RMS
SONET_OC48, 12 kHz to 20 MHz	315 fs
SONET_OC192_A, 20 kHz to 80 MHz	335 fs
SONET_OC192_B, 4 MHz to 80 MHz	194 fs
SONET_OC192_C, 50 kHz to 80 MHz	318 fs
Brick Wall, 800 Hz to 80 MHz	343 fs

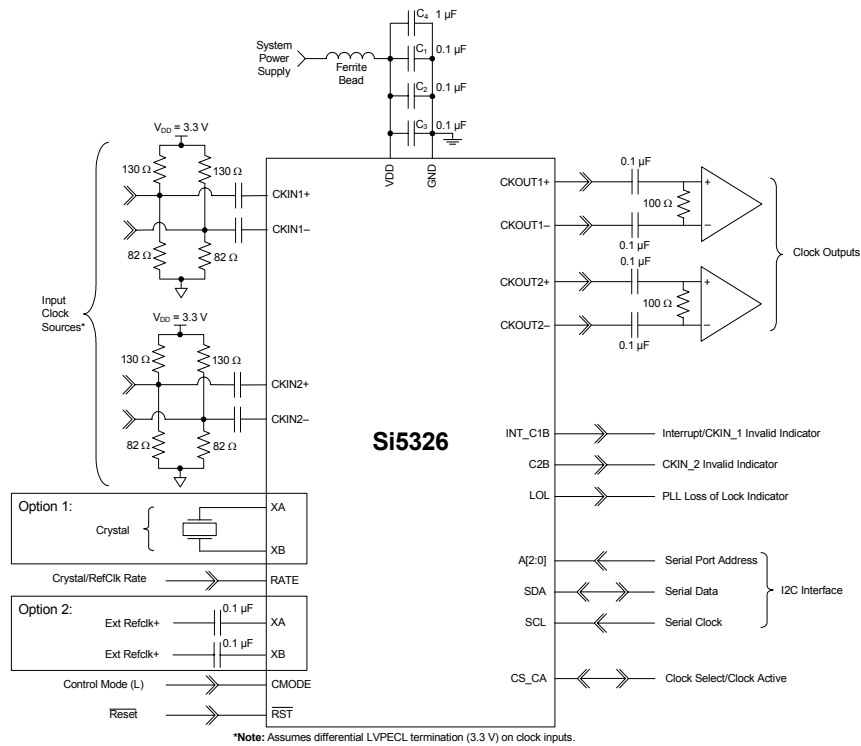


Figure 2. Si5326 Typical Application Circuit (I²C Control Mode)

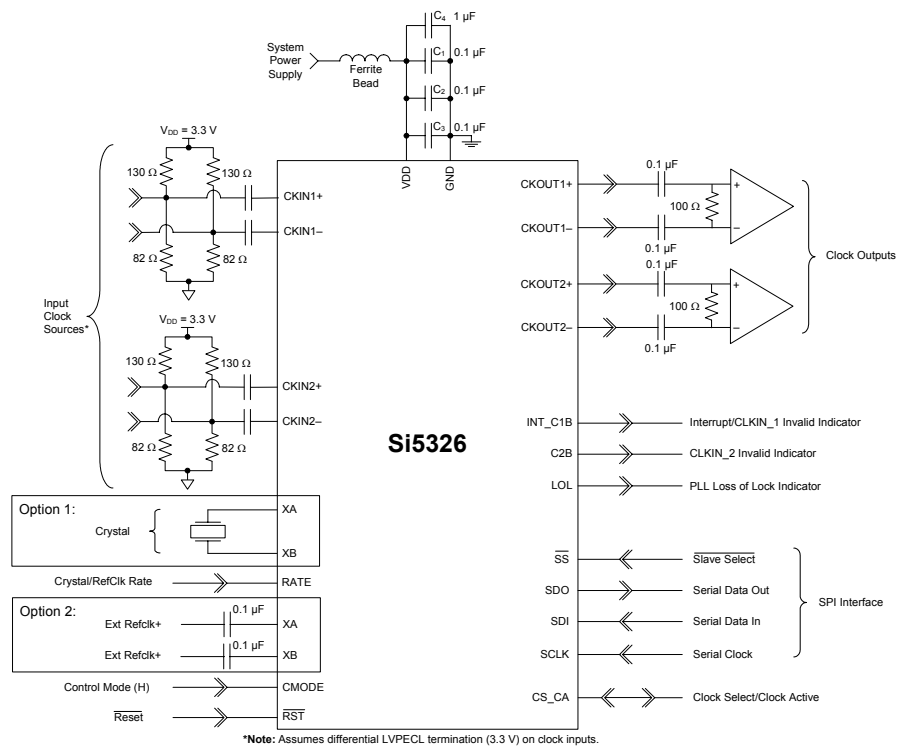


Figure 3. Si5326 Typical Application Circuit (SPI Control Mode)

1. Functional Description

The Si5326 is a jitter-attenuating precision clock multiplier for applications requiring sub 1 ps jitter performance. The Si5326 accepts two input clocks ranging from 2 kHz to 710 MHz and generates two output clocks ranging from 2 kHz to 945 MHz and select frequencies to 1.4 GHz. The Si5326 can also use its crystal oscillator as a clock source for frequency synthesis. The device provides virtually any frequency translation combination across this operating range. Independent dividers are available for each input clock and output clock, so the Si5326 can accept input clocks at different frequencies and it can generate output clocks at different frequencies. The Si5326 input clock frequency and clock multiplication ratio are programmable through an I²C or SPI interface. Silicon Laboratories offers a PC-based software utility, *DSPLLsim*, that can be used to determine the optimum PLL divider settings for a given input frequency/clock multiplication ratio combination that minimizes phase noise and power consumption. This utility can be downloaded from <http://www.silabs.com/timing>; click on Documentation.

The Si5326 is based on Silicon Laboratories' 3rd-generation DSPLL[®] technology, which provides any-rate frequency synthesis and jitter attenuation in a highly integrated PLL solution that eliminates the need for external VCXO and loop filter components. The Si5326 PLL loop bandwidth is digitally programmable and supports a range from 60 Hz to 8.4 kHz. The *DSPLLsim* software utility can be used to calculate valid loop bandwidth settings for a given input clock frequency/clock multiplication ratio.

The Si5326 supports hitless switching between the two synchronous input clocks in compliance with GR-253-CORE that greatly minimizes the propagation of phase transients to the clock outputs during an input clock transition (maximum 200 ps phase change). Manual and automatic revertive and non-revertive input clock switching options are available. The Si5326 monitors both input clocks for loss-of-signal and provides a LOS alarm when it detects missing pulses on either input clock. The device monitors the lock status of the PLL. The lock detect algorithm works by continuously monitoring the phase of the input clock in relation to the phase of the feedback clock. The Si5326 also monitors frequency offset alarms (FOS), which indicate if an input clock is within a specified frequency precision relative to the frequency of a reference clock. Both Stratum 3/3E and SONET Minimum Clock (SMC) FOS thresholds are supported.

The Si5326 provides a digital hold capability that allows the device to continue generation of a stable output clock when the selected input reference is lost. During digital hold, the DSPLL generates an output frequency

based on a historical average frequency that existed a fixed amount of time before the error event occurred, eliminating the effects of phase and frequency transients that may occur immediately preceding digital hold.

The Si5326 has two differential clock outputs. The electrical format of each clock output is independently programmable to support LVPECL, LVDS, CML, or CMOS loads. If not required, the second clock output can be powered down to minimize power consumption. The phase difference between the selected input clock and the output clocks is adjustable in 200 ps increments for system skew control using the *CLAT*[7:0] register. Fine phase adjustment is available and is set using the *FLAT* register bits. The nominal range and resolution of the *FLAT*[14:0] latency adjustment word are: ± 110 ps and 3 ps, respectively. In addition, the phase of one output clock may be adjusted in relation to the phase of the other output clock. The resolution varies from 800 ps to 2.2 ns depending on the PLL divider settings. The *DSPLLsim* software utility determines the phase offset resolution for a given input clock/clock multiplication ratio combination. For system-level debugging, a bypass mode is available which drives the output clock directly from the input clock, bypassing the internal DSPLL. The device is powered by a single 1.8, 2.5, or 3.3 V supply.

1.1. External Reference

An external, high quality 38.88 MHz clock or a low-cost 114.285 MHz 3rd overtone crystal is used as part of a fixed-frequency oscillator within the DSPLL. This external reference is required for the device to perform jitter attenuation. Silicon Laboratories recommends using a high quality crystal. Specific recommendations may be found in the Family Reference Manual.

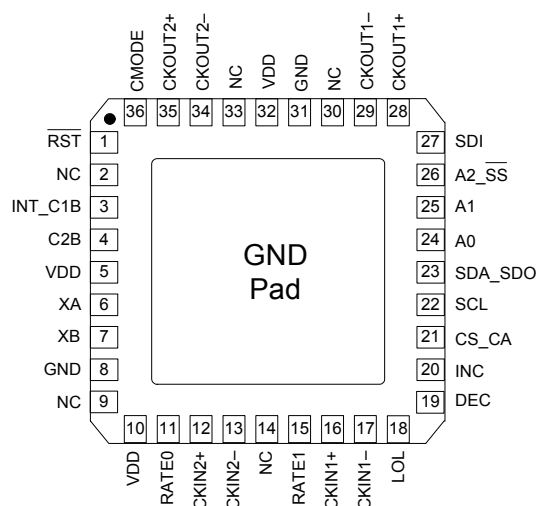
In digital hold, the DSPLL remains locked and tracks external reference. Note that crystals can have temperature sensitivities.

1.2. Further Documentation

Consult the Silicon Laboratories Any-Rate Precision Clock Family Reference Manual (FRM) for detailed information about the Si5326. Additional design support is available from Silicon Laboratories through your distributor.

Silicon Laboratories has developed a PC-based software utility called *DSPLLsim* to simplify device configuration, including frequency planning and loop bandwidth selection. The FRM and this utility can be downloaded from <http://www.silabs.com/timing>; click on Documentation.

2. Pin Descriptions: Si5326



Pin numbers are preliminary and subject to change.

Pin #	Pin Name	I/O	Signal Level	Description
1	$\overline{\text{RST}}$	I	LVC MOS	<p>External Reset.</p> <p>Active low input that performs external hardware reset of device. Resets all internal logic to a known state and forces the device registers to their default value. Clock outputs are tristated during reset. The part must be programmed after a reset or power-on to get a clock output. See Family Reference Manual for details.</p> <p>This pin has a weak pull-up.</p>
2, 9, 14, 30, 33	NC	—	—	<p>No Connect.</p> <p>This pin must be left unconnected for normal operation.</p>
3	INT_C1B	O	LVC MOS	<p>Interrupt/CKIN1 Invalid Indicator.</p> <p>This pin functions as a device interrupt output or an alarm output for CKIN1. If used as an interrupt output, <i>INT_PIN</i> must be set to 1. The pin functions as a maskable interrupt output with active polarity controlled by the <i>INT_POL</i> register bit.</p> <p>If used as an alarm output, the pin functions as a LOS (and optionally FOS) alarm indicator for CKIN1. Set <i>CK1_BAD_PIN</i> = 1 and <i>INT_PIN</i> = 0.</p> <p>0 = CKIN1 present. 1 = LOS (FOS) on CKIN1.</p> <p>The active polarity is controlled by <i>CK_BAD_POL</i>. If no function is selected, the pin tristates.</p>
<p>Note: Internal register names are indicated by underlined italics, e.g. <i>INT_PIN</i>. See Si5326 Register Map.</p>				

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Pin #	Pin Name	I/O	Signal Level	Description						
4	C2B	O	LVC MOS	<p>CKIN2 Invalid Indicator.</p> <p>This pin functions as a LOS (and optionally FOS) alarm indicator for CKIN2 if <u>CK2_BAD_PIN</u> = 1.</p> <p>0 = CKIN2 present.</p> <p>1 = LOS (FOS) on CKIN2.</p> <p>The active polarity can be changed by <u>CK_BAD_POL</u>. If <u>CK2_BAD_PIN</u> = 0, the pin tristates.</p>						
5, 10, 32	V _{DD}	V _{DD}	Supply	<p>Supply.</p> <p>The device operates from a 1.8, 2.5, or 3.3 V supply. Bypass capacitors should be associated with the following V_{DD} pins:</p> <table border="0"> <tr> <td>5</td> <td>0.1 μF</td> </tr> <tr> <td>10</td> <td>0.1 μF</td> </tr> <tr> <td>32</td> <td>0.1 μF</td> </tr> </table> <p>A 1.0 μF should also be placed as close to the device as is practical.</p>	5	0.1 μF	10	0.1 μF	32	0.1 μF
5	0.1 μF									
10	0.1 μF									
32	0.1 μF									
7 6	XB XA	I	Analog	<p>External Crystal or Reference Clock.</p> <p>External crystal should be connected to these pins to use internal oscillator based reference. Refer to Family Reference Manual for interfacing to an external reference. External reference must be from a high-quality clock source (TCXO, OCXO). Frequency of crystal or external clock is set by RATE[1:0] pins.</p>						
8, 31	GND	GND	Supply	<p>Ground.</p> <p>Must be connected to system ground. Minimize the ground path impedance for optimal performance of this device. Grounding these pins does not eliminate the requirement to ground the GND PAD on the bottom of the package.</p>						
11 15	RATE0 RATE1	I	3-Level	<p>External Crystal or Reference Clock Rate.</p> <p>Three level inputs that select the type and rate of external crystal or reference clock to be applied to the XA/XB port. Refer to the Family Reference Manual for settings. These pins have both a weak pull-up and a weak pull-down; they default to M.</p> <p>Note: HH setting converts port to Si5325. L setting corresponds to ground. M setting corresponds to V_{DD}/2. H setting corresponds to V_{DD}.</p> <p>Some designs may require an external resistor voltage divider when driven by an active device that will tri-state.</p>						
16 17	CKIN1+ CKIN1–	I	Multi	<p>Clock Input 1.</p> <p>Differential input clock. This input can also be driven with a single-ended signal. Input frequency range is 2 kHz to 710 MHz.</p>						
12 13	CKIN2+ CKIN2–	I	Multi	<p>Clock Input 2.</p> <p>Differential input clock. This input can also be driven with a single-ended signal. Input frequency range is 2 kHz to 710 MHz.</p>						
<p>Note: Internal register names are indicated by underlined italics, e.g. <u>INT_PIN</u>. See Si5326 Register Map.</p>										

Pin #	Pin Name	I/O	Signal Level	Description
18	LOL	O	LVC MOS	<p>PLL Loss of Lock Indicator.</p> <p>This pin functions as the active high PLL loss of lock indicator if the <u>LOL_PIN</u> register bit is set to 1.</p> <p>0 = PLL locked. 1 = PLL unlocked.</p> <p>If <u>LOL_PIN</u> = 0, this pin will tristate. Active polarity is controlled by the <u>LOL_POL</u> bit. The PLL lock status will always be reflected in the <u>LOL_INT</u> read only register bit.</p>
19	DEC	I	LVC MOS	<p>Latency Decrement.</p> <p>A pulse on this pin decreases the input to output device latency by $1/f_{OSC}$ (approximately 200 ps). There is no limit on the range of latency adjustment by this method.</p> <p>Pin control is enabled by setting <u>INCDEC_PIN</u> = 1. If <u>INCDEC_PIN</u> = 0, this pin is ignored and output latency is controlled via the <u>CLAT</u> register.</p> <p>If both INC and DEC are tied high, phase buildout is disabled and the device maintains a fixed-phase relationship between the selected input clock and the output clock during an input clock switch.</p> <p>See the Family Reference Manual for more details. This pin has a weak pull-down.</p>
20	INC	I	LVC MOS	<p>Latency Increment.</p> <p>A pulse on this pin increases the input to output device latency by $1/f_{OSC}$ (approximately 200 ps). There is no limit on the range of latency adjustment by this method.</p> <p>Pin control is enabled by setting <u>INCDEC_PIN</u> = 1. If <u>INCDEC_PIN</u> = 0, this pin is ignored and output latency is controlled via the <u>CLAT</u> register.</p> <p>If both INC and DEC are tied high, phase buildout is disabled and the device maintains a fixed-phase relationship between the selected input clock and the output clock during an input clock switch.</p> <p>See the Family Reference Manual for more details. Note: INC does not increase latency if NI_HS = 4. This pin has a weak pull-down.</p>
<p>Note: Internal register names are indicated by underlined italics, e.g. <u>INT_PIN</u>. See Si5326 Register Map.</p>				

Pin #	Pin Name	I/O	Signal Level	Description
21	CS_CA	I/O	LVC MOS	<p>Input Clock Select/Active Clock Indicator.</p> <p>Input: In manual clock selection mode, this pin functions as the manual input clock selector if the <u>CKSEL_PIN</u> is set to 1. 0 = Select CKIN1. 1 = Select CKIN2. If <u>CKSEL_PIN</u> = 0, the <u>CKSEL_REG</u> register bit controls this function and this input tristates. If configured for input, must be tied high or low.</p> <p>Output: In automatic clock selection mode, this pin indicates which of the two input clocks is currently the active clock. If alarms exist on both clocks, CK_ACTV will indicate the last active clock that was used before entering the digital hold state. The <u>CK_ACTV_PIN</u> register bit must be set to 1 to reflect the active clock status to the CK_ACTV output pin. 0 = CKIN1 active input clock. 1 = CKIN2 active input clock. If <u>CK_ACTV_PIN</u> = 0, this pin will tristate. The CK_ACTV status will always be reflected in the <u>CK_ACTV_REG</u> read only register bit.</p>
22	SCL	I	LVC MOS	<p>Serial Clock.</p> <p>This pin functions as the serial clock input for both SPI and I²C modes. This pin has a weak pull-down.</p>
23	SDA_SDO	I/O	LVC MOS	<p>Serial Data.</p> <p>In I²C control mode (CMODE = 0), this pin functions as the bidirectional serial data port. In SPI control mode (CMODE = 1), this pin functions as the serial data output.</p>
25 24	A1 A0	I	LVC MOS	<p>Serial Port Address.</p> <p>In I²C control mode (CMODE = 0), these pins function as hardware controlled address bits. The I²C address is 1101 [A2] [A1] [A0]. In SPI control mode (CMODE = 1), these pins are ignored. These pins have a weak pull-down.</p>
26	A2_SS	I	LVC MOS	<p>Serial Port Address/Slave Select.</p> <p>In I²C control mode (CMODE = 0), this pin functions as a hardware controlled address bit [A2]. In SPI control mode (CMODE = 1), this pin functions as the slave select input. This pin has a weak pull-down.</p>
27	SDI	I	LVC MOS	<p>Serial Data In.</p> <p>In I²C control mode (CMODE = 0), this pin is ignored. In SPI control mode (CMODE = 1), this pin functions as the serial data input. This pin has a weak pull-down.</p>
<p>Note: Internal register names are indicated by underlined italics, e.g. <u>INT_PIN</u>. See Si5326 Register Map.</p>				

Pin #	Pin Name	I/O	Signal Level	Description
29 28	CKOUT1– CKOUT1+	O	Multi	Output Clock 1. Differential output clock with a frequency range of 10 MHz to 1.4175 GHz. Output signal format is selected by <u><i>SFOUT1_REG</i></u> register bits. Output is differential for LVPECL, LVDS, and CML compatible modes. For CMOS format, both output pins drive identical single-ended clock outputs.
34 35	CKOUT2– CKOUT2+	O	Multi	Output Clock 2. Differential output clock with a frequency range of 10 MHz to 1.4175 GHz. Output signal format is selected by <u><i>SFOUT2_REG</i></u> register bits. Output is differential for LVPECL, LVDS, and CML compatible modes. For CMOS format, both output pins drive identical single-ended clock outputs.
36	CMODE	I	LVC MOS	Control Mode. Selects I ² C or SPI control mode for the Si5326. 0 = I ² C Control Mode 1 = SPI Control Mode This pin must not be NC. Tie either high or low.
GND PAD	GND	GND	Supply	Ground Pad. The ground pad must provide a low thermal and electrical impedance to a ground plane.
Note: Internal register names are indicated by underlined italics, e.g. <u><i>INT_PIN</i></u> . See Si5326 Register Map.				

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3. Ordering Guide

Ordering Part Number	Output Clock Frequency Range	Package	ROHS6, Pb-Free	Temperature Range
Si5326A-C-GM	2 kHz–945 MHz 970–1134 MHz 1.213–1.417 GHz	36-Lead 6 x 6 mm QFN	Yes	–40 to 85 °C
Si5326B-C-GM	2 kHz–808 MHz	36-Lead 6 x 6 mm QFN	Yes	–40 to 85 °C
Si5326C-C-GM	2 kHz–346 MHz	36-Lead 6 x 6 mm QFN	Yes	–40 to 85 °C

Note: Add an R at the end of the device to denote tape and reel options.

4. Package Outline: 36-Pin QFN

Figure 4 illustrates the package details for the Si5326. Table 3 lists the values for the dimensions shown in the illustration.

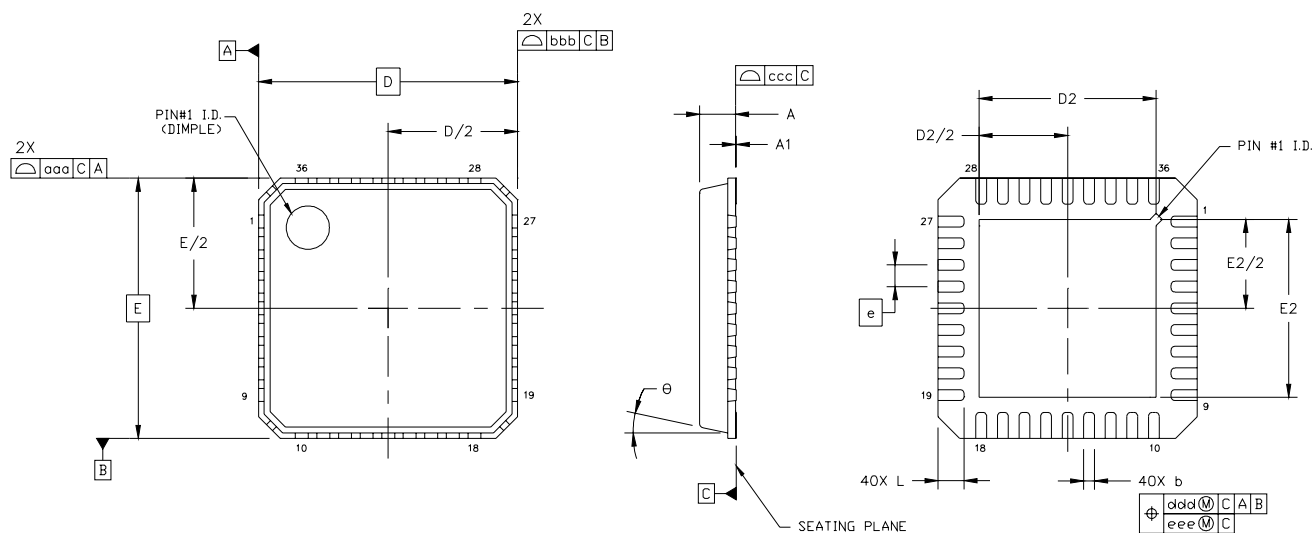


Figure 4. 36-Pin Quad Flat No-lead (QFN)

Table 3. Package Dimensions

Symbol	Millimeters		
	Min	Nom	Max
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D	6.00 BSC		
D2	3.95	4.10	4.25
e	0.50 BSC		
E	6.00 BSC		
E2	3.95	4.10	4.25

Symbol	Millimeters		
	Min	Nom	Max
L	0.50	0.60	0.70
θ	—	—	12°
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.05

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-220, variation VJJD.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

5. Recommended PCB Layout

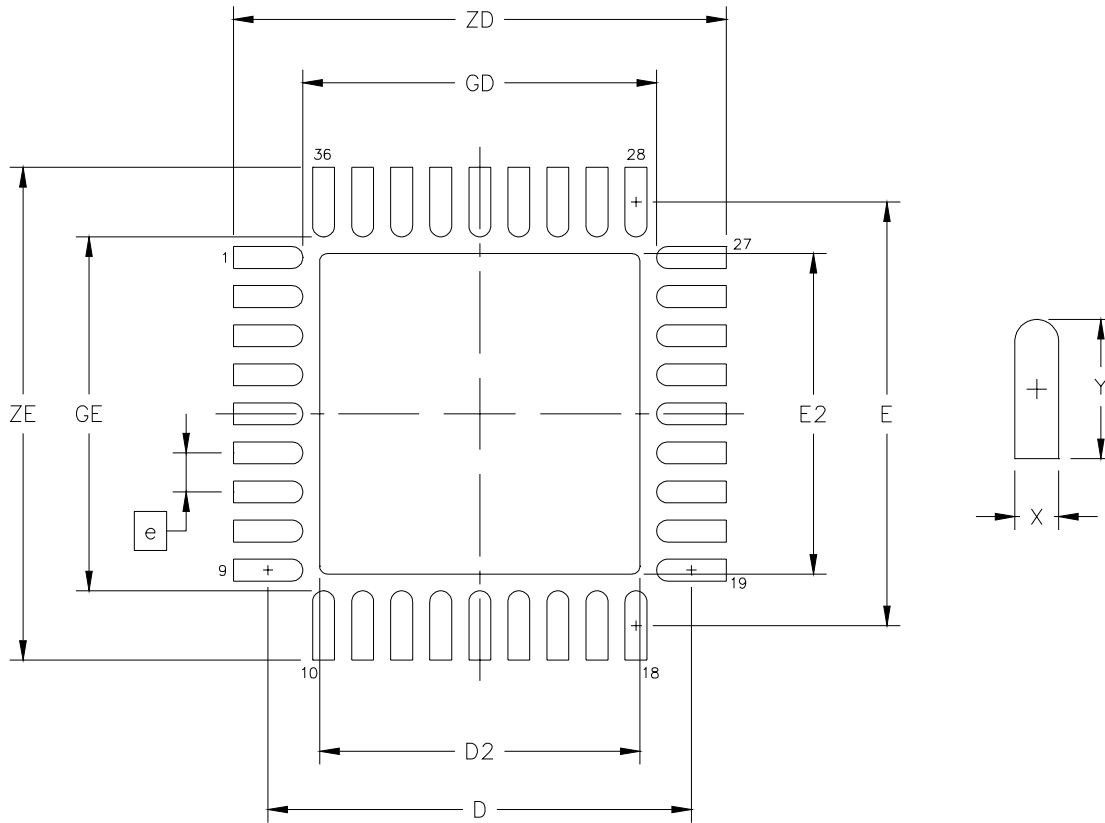


Figure 5. PCB Land Pattern Diagram

Table 4. PCB Land Pattern Dimensions

Dimension	MIN	MAX
e	0.50 BSC.	
E	5.42 REF.	
D	5.42 REF.	
E2	4.00	4.20
D2	4.00	4.20
GE	4.53	—
GD	4.53	—
X	—	0.28
Y	0.89 REF.	
ZE	—	6.31
ZD	—	6.31

Notes (General):

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on IPC-SM-782 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Notes (Solder Mask Design):

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.

Notes (Stencil Design):

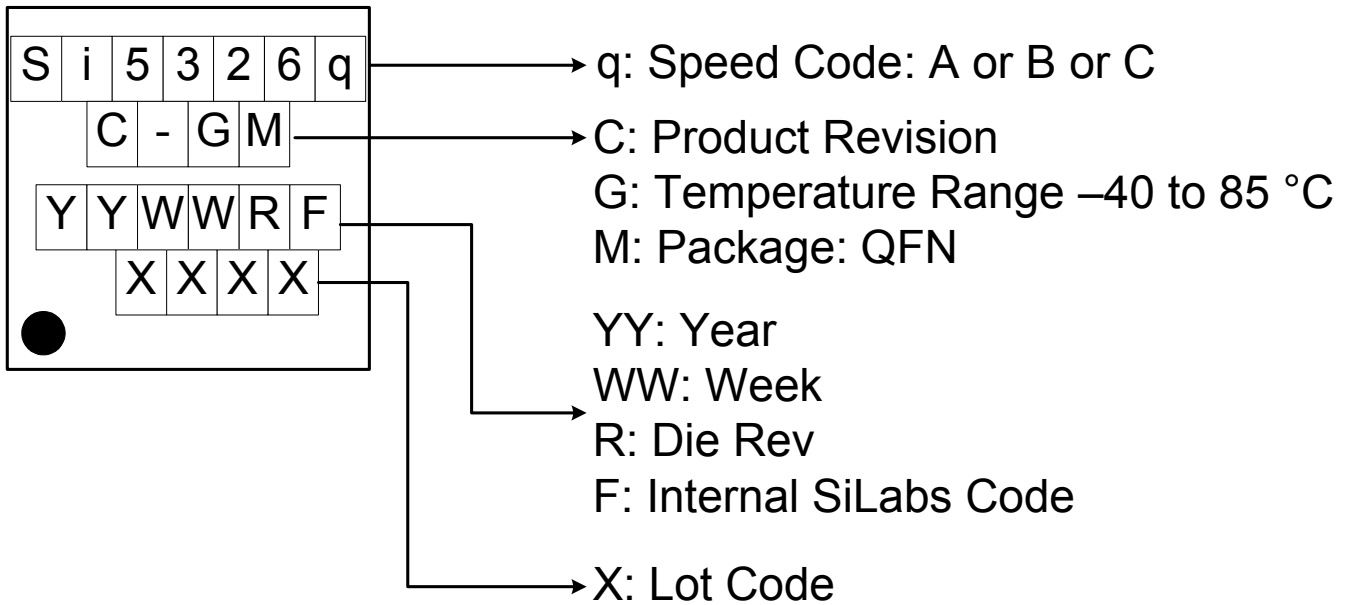
1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
4. A 4 x 4 array of 0.80 mm square openings on 1.05 mm pitch should be used for the center ground pad.

Notes (Card Assembly):

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

Si5326

6. Si5326 Device Top Mark



DOCUMENT CHANGE LIST

Revision 0.1 to Revision 0.2

- Updated LVTTTL to LVCMOS in Table 2, “Absolute Maximum Ratings,” on page 3.
- Added Figure 1, “Typical Phase Noise Plot,” on page 4.
- Updated Figure 2, “Si5326 Typical Application Circuit (I²C Control Mode),” and Figure 3, “Si5326 Typical Application Circuit (SPI Control Mode),” on page 5 to show preferred external reference interface.
- Updated “2. Pin Descriptions: Si5326”.
 - Added RATE0 and changed RATE to RATE1 and expanded RATE[1:0] description.
 - Changed font of register names to *underlined italics*.
- Updated “3. Ordering Guide” on page 12.
- Added “4. Package Outline: 36-Pin QFN” on page 13.
- Added “5. Recommended PCB Layout”.

Revision 0.2 to Revision 0.3

- Changed 1.8 V operating range to $\pm 5\%$.
- Updated Table 1 on page 2.
- Updated Table 2 on page 3.
- Updated Table 3 on page 13.
- Added table under Figure 1 on page 4.
- Updated “1. Functional Description” on page 6.
- Clarified “2. Pin Descriptions: Si5326” on page 7 including pull-up/pull-down.

Revision 0.3 to Revision 0.4

- Updated Table 1 on page 2.
- Added “6. Si5326 Device Top Mark” on page 16.

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